



Docket No.: 06920/000K024-US0  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Yasuyuki Inoue

Application No.: 10/037,696

Confirmation No.: 7564

Filed: November 9, 2001

Art Unit: 2133

For: SEMICONDUCTOR TEST APPARATUS

Examiner: J. P. Trimmings

**AMENDMENT AFTER FINAL ACTION (37 C.F.R. SECTION 1.116)**

MS AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

*OK to enter  
per RCE 6-21-05  
pay*

**INTRODUCTORY COMMENTS**

In response to the Office Action dated January 27, 2005 (Paper No. 01102005), and subject to the approval of the Examiner, please amend the above-identified U.S. patent application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.